

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10574395	NAGANO ET AL.
	Examiner	Art Unit
	IYAD TOOM	3744

SEARCHED

Class	Subclass	Date	Examiner
236	93B, 93R, 99R, 99K, 99J, 93A	2009-2-25	IFT
137	137/468, 625, 625.18, 594, 595 and text search	2009-2-25	IFT

SEARCH NOTES

Search Notes	Date	Examiner
met primary examiner Marc Norman, contacted primary examiner Chen-Wen Jiang and met primary examiner John Rivell for search.	2009-2-25	IFT
East(USPGPUB, USPAT, EPO, JPO, Derwent) and east inventor search	2009-2-25	IFT

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

/IYAD TOOM/
Examiner.Art Unit 3744